

Strain engineering of anisotropic light–matter interactions in one-dimensional P–P chain of SiP₂

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ABSTRACT

Strain engineering can serve as a powerful technique for modulating the exotic properties arising from the atomic structure of materials. Examples have been demonstrated that one-dimensional (1D) structure can serve as a great platform for modulating electronic band structure and phonon dispersion via strain control. Particularly, in a van der Waals material silicon diphosphide (SiP₂), quasi-1D zigzag phosphorus–phosphorus (P–P) chains are embedded inside the crystal structure, and can show unique phonon vibration modes and realize quasi-1D excitons. Manipulating those optical properties by the atom displacements via strain engineering is of great interest in understanding underlying mechanism of such P–P chains, however, which remains elusive. Herein, we demonstrate the strain engineering of Raman and photoluminescence (PL) spectra in quasi-1D P–P chains and resulting in anisotropic manipulation in SiP₂. We find that the phonon frequencies of SiP₂ in Raman spectra linearly evolve with a uniaxial strain along/perpendicular to the quasi-1D P–P chain directions. Interestingly, by applying tensile strain along the P–P chains, the band gap energy of strained SiP₂ can significantly decrease with a tunable value of ~ 55 meV. Based on arsenic (As) element doping into SiP₂, the strain-induced redshifts of phonon frequencies decrease, indicating the stiffening of the phonon vibration with the increased arsenic doping level. Such results provide an opportunity for strain engineering of the light–matter interactions in the quasi-1D P–P chains of SiP₂ crystal for potential optical applications.

KEYWORDS

strain engineering, silicon diphosphide, Raman, photoluminescence

1 Introduction

Anisotropic crystal structures and reduced crystal symmetry of materials play key roles in determining their electronic and optical properties [1–6]. Examples of anisotropic crystal structures have been found in layered two-dimensional (2D) materials such as black phosphorus (BP) [7], ReS₂ [8], TiS₃ [9], and ZrS₃ [10]. Unlike materials with high symmetry showing isotropic physical properties, many 2D materials with reduced crystal symmetry display strong in-plane anisotropic properties. Such an anisotropic crystal structure results in an apparently distinct response when applying strain along different crystalline orientations [11]. Uniaxial mechanical strain can usually serve as a powerful way to modulate light–matter interactions by manipulating the crystal structure and thus is of great interest and significance in practical applications such as strain sensors and polarization-sensitive detectors [12–15]. Among a variety of material candidates, van der Waals 2D materials are particularly suitable for local strain engineering due to their atomically thin thickness and great flexibility [16–19]. Therefore, it is highly desirable to study the strain engineering of Raman and photoluminescence (PL)

characteristics for phonon vibration modes and excitonic states in anisotropic 2D materials [20–23].

Herein, combined with optical measurements of the Raman and PL spectra, we demonstrate that strain engineering can effectively manipulate the phonon frequencies as well as the band gap energy in anisotropic layered SiP₂. The phonon frequencies of SiP₂ decrease gradually and linearly with applying uniaxial tensile strain along the phosphorus–phosphorus (P–P) chain direction in the SiP₂ crystal, while those frequencies increase with uniaxial tensile strain applied perpendicularly. Interestingly, we find that the phonon vibration becomes stiff when arsenic (As) is intentionally doped into SiP₂, and thus, the atomic bonding strength between atoms in the crystal is increased. Note that in the PL spectra of wrinkled flakes, the strain can induce redshifts of the peak in the PL spectra, and the decreased values in the optical band gap of SiP₂ can be as significant as ~ 55 meV, indicating that strain engineering can produce large deformations of the lattice structure related to the P–P chains and lead to the evolution of the energy band structure in layered SiP₂. Such results support the view that strain engineering can serve as an enabling tool to

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explore novel physics originating from the zigzag P–P chains in SiP₂, providing an effective method to manipulate the atomic structure and tune the specific optical properties of 2D materials for potential optical applications.

2 Experiments

We intentionally chose in-plane anisotropic SiP₂ to study strain engineering for tuning the Raman and PL properties for the following reasons. First, the atomic structure of SiP₂ has an orthorhombic structure with in-plane lattice constants $a = 10.091 \text{ \AA}$ and $b = 3.439 \text{ \AA}$ (space group No. 62, $Pnma$) [24–26], providing strong in-plane anisotropy, as schematically shown in Fig. 1(a). Second, SiP₂ contains two kinds of inequivalent phosphorus atomic sites distinguished by their bonding surroundings. For the P atom bonding to one Si atom and two other P atoms, those neighboring P atoms bond together, forming embedded quasi-one-dimensional (quasi-1D) zigzag P–P chains along the y direction. Note that such zigzag P–P chains can generate highly anisotropic phonon vibrations and PL properties in SiP₂, which will be one of the main focuses of this study. Third, an exotic excitonic state with strong anisotropy originates from the unique quasi-1D electronic state along the zigzag P–P chains in SiP₂. Therein, emergent many-body phenomena are related to the exciton–phonon interaction. Therefore, in-plane anisotropic SiP₂ can serve as a unique material platform to investigate the phonon vibration modes and excitonic states via strain engineering.

Two methods were used to apply strain for the Raman and PL measurements. On the one hand, as shown in Fig. 1(a), polyethylene terephthalate (PET) was used as a flexible substrate for applying tensile strain on few-layer SiP₂ for strain-dependent Raman spectra measurements. The SiP₂ flakes were mechanically exfoliated with polydimethylsiloxane (PDMS) and directly transferred onto the surface of a flexible PET substrate [27], which was processed inside a glove box (protected with 99.99% purity N₂) to prevent the sample from oxidizing. To identify the direction of applied strain, we found that the exfoliated SiP₂ flake had a

rectangular shape in which the long and short edges corresponded to the y and x directions (more details are shown in Figs. S1 and S2 in the Electronic Supplementary Material (ESM)). On the other hand, for strain-dependent PL spectra measurements, a wrinkled flake was intentionally generated by transferring the sample onto i) pre-stretched PDMS or ii) Si/SiO₂ substrate with pre-patterned SiO₂ nanowires. Atomic force microscopy (AFM) was used to identify the thickness of the samples and the shape of the wrinkled structure. In optical measurements, both Raman and PL spectra were obtained by the WITec Alpha 300 system at room temperature using a $\times 50$ objective lens. The laser had a wavelength of 532 nm and power of 1 mW. The integrated time was 20 seconds and was repeated 5 times. All optical measurements were performed under the protection of a N₂ atmosphere (99.99% purity). Normally, the uniaxial tensile strain value ε applied on the sample can be estimated by $\varepsilon \sim \Delta L/L_0$, where L_0 is the initial length of a SiP₂ flake before applying strain, and ΔL is the increased length of the sample after stretching. The values of L_0 and ΔL can be obtained from the optical images of the strained SiP₂ flake, and the measurement method and results are shown in Figs. S1–S3 in the ESM.

3 Results and discussion

3.1 Raman spectra of SiP₂ under uniaxial tensile strain

To detect the strain response of the vibration modes in layered SiP₂ thin flakes, we performed Raman measurements based on a homemade mechanical strain stage with PET as a flexible supporting substrate (shown in Fig. S4 in the ESM). With this stage, we can precisely control the magnitude of uniaxial tensile strain applied along the y and x directions in SiP₂, as shown in Fig. 1(b). Note that the strain is uniformly distributed in the entire SiP₂ flake, which is confirmed by the Raman mapping image in Fig. S4(c) in the ESM. Since the lattice symmetry does not change during stretching (shown in Fig. S5 in the ESM), applied strain can only cause the shift of the Raman peaks without symmetry-

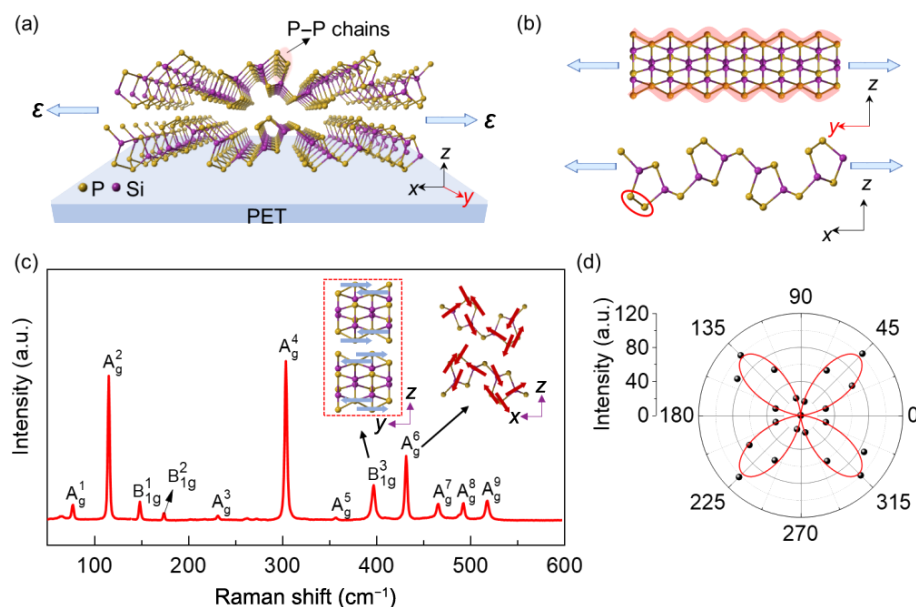


Figure 1 Crystal structure and schematic illustration of strain engineering of SiP₂. (a) Schematic diagram of a strained SiP₂ crystal, where PET is selected as a flexible substrate. Si and P atoms are represented by purple and yellow spheres, respectively. The xyz coordinate system is defined based on the crystal structure, as shown in the lower right corner. The quasi-1D zigzag P–P chains are embedded along the y direction (highlighted by pink shadow). Blue arrows display the direction of tension when applying strain. (b) Uniaxial strain applied along two perpendicular directions of the SiP₂ crystal. The upper (or lower) panel shows stretching along the y (or x) direction, and the P–P chains are highlighted. (c) Raman spectrum of a SiP₂ thin flake excited by a 532-nm laser. The characteristic vibration modes are labeled. The inset shows the vibration modes of B_{31g} (left panel) and A_{6g} (right panel). (d) Polar plot of the Raman peak intensity of the B_{31g} mode from polarized Raman spectra, which indicates the fourfold symmetry of Raman scattering tensor elements.

breaking-induced splitting, which provides an advantage to study the anisotropic Raman spectra under strain. Figure 1(c) shows the Raman spectrum of a few-layer pristine SiP₂ with no strain. Twelve Raman peaks are labeled as A_g¹ (77 cm⁻¹), A_g² (116 cm⁻¹), B_{1g}¹ (149 cm⁻¹), B_{1g}² (174 cm⁻¹), A_g³ (232 cm⁻¹), A_g⁴ (304 cm⁻¹), A_g⁵ (358 cm⁻¹), B_{1g}³ (398 cm⁻¹), A_g⁶ (433 cm⁻¹), A_g⁷ (467 cm⁻¹), A_g⁸ (494 cm⁻¹), and A_g⁹ (519 cm⁻¹), are consistent with previous Raman studies on SiP₂ [28]. The B_{1g}³ Raman peak reflects the characteristic vibration modes of the P–P chains, as schematically represented in the inset of Fig. 1(c) and Fig. S6 in the ESM. From the polarized Raman spectra shown in Fig. 1(d), one can see that the B_{1g}³ mode related to the P–P chains in SiP₂ shows fourfold rotational symmetry. In this study, we will mainly investigate B_{1g}³ and A_g⁶ vibration modes, which are the most sensitive to the applied strain in our experiments.

Figure 2(a) shows the evolution of the Raman spectra of few-layer SiP₂ with increased strain from 0% to 1.07% along the *y* direction. One can see in Figs. 2(b) and 2(c) that both B_{1g}³ and A_g⁶ peaks shift to lower wavenumbers with increased strain. The B_{1g}³ peak shows a more obvious redshift than the A_g⁶ peak, suggesting that the former is more sensitive to strain than the latter. To describe this sensitivity quantitatively, we calculate the average slope Δ (cm⁻¹/%), which is obtained from the linear fit to the Raman shift data as a function of applied strain. Thus, the Δ_x and Δ_y values represent the strain response of the strain along the *x* and *y* directions of SiP₂, respectively. Along the *y* direction, when ϵ is up to 1.07%, the B_{1g}³ peak shows a redshift with $\Delta_y = -7.06$ cm⁻¹/%, and the A_g⁶ peak shows a redshift with $\Delta_y = -4.81$ cm⁻¹/%. In contrast, in Figs. 2(d)–2(f), when ϵ along the *x*

direction is increased from 0% to 4.65%, both B_{1g}³ and A_g⁶ peaks show blueshifts. The Δ_x values of B_{1g}³ and A_g⁶ peaks are approximately 2.05 cm⁻¹/% and 0.90 cm⁻¹/%, respectively. One can see that the Δ_y values are significantly greater than the Δ_x values, indicating that SiP₂ is a highly anisotropic material and shows a higher strain-dependent sensitivity along the P–P chains. The intensity of both B_{1g}³ and A_g⁶ peaks decreases with increasing strain in the *y* and *x* directions (shown in Fig. S7 in the ESM).

To further understand the microscopic atomic displacements of strained SiP₂, we calculated Poisson's ratio σ (defined as $-\Delta_x/\Delta_y$) for B_{1g}³ and A_g⁶ Raman modes, which are sensitive to atomic bonding strength. From Figs. 2(c) and 2(f), the σ value for the A_g⁶ mode is estimated to be approximately 0.19, consistent with the value of 0.16 obtained from the optical microscopy image (shown in Table S1 and Fig. S8 in the ESM). SiP₂ has a greater Poisson's ratio than MoS₂ ($\sigma = 0.125$) [29], indicating the strong strain-dependent anisotropy of SiP₂. In contrast, from Figs. 2(b) and 2(e), Poisson's ratio for the B_{1g}³ Raman mode is estimated to be approximately 0.29. The significant difference in the Poisson's ratio of B_{1g}³ and A_g⁶ Raman modes can be attributed to the following reason. The atomic vibration of the B_{1g}³ mode only involves those P atoms within the P–P chains. Due to the particular atomic structure of SiP₂, the uniaxial tensile strain along the *x* direction (perpendicular to the P–P chains) can cause larger position displacements of those P atoms within the P–P chains than that of Si atoms and the remaining P atoms. In contrast, the atomic displacements of all atoms under strain along the *y* direction are similar. Therefore, the uniaxial tensile strain along the *x* direction contributes to a larger shift of the B_{1g}³ peak and leads to an overestimation of Poisson's ratio.

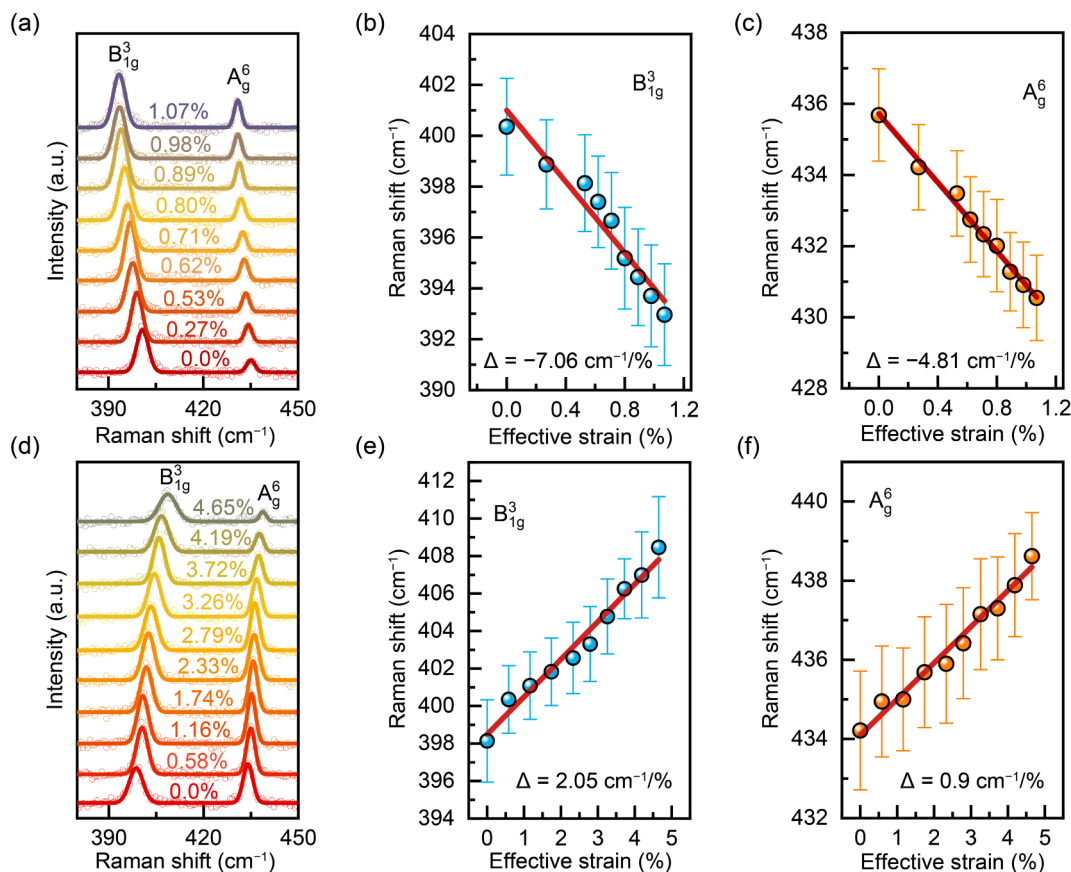


Figure 2 Anisotropic response of Raman spectra of SiP₂ under strain along different directions. (a) Evolution of Raman spectra of a SiP₂ thin flake under strain applied along the *y* direction. With increased strain up to 1.07%, both B_{1g}³ and A_g⁶ modes show redshifts. (b) and (c) Evolution of Raman shifts of both B_{1g}³ and A_g⁶ modes under strain along the *y* direction. Both B_{1g}³ and A_g⁶ modes show linear redshifts whose values depend on tensile strain along the *y* direction. (d) Evolution of Raman spectra of a SiP₂ thin flake under strain applied along the *x* direction. With increased strain up to 4.65%, both B_{1g}³ and A_g⁶ modes show blueshifts. (e) and (f) Evolution of Raman shifts of both B_{1g}³ and A_g⁶ modes under strain along the *x* direction. Both B_{1g}³ and A_g⁶ modes show linear blueshifts whose values depend on tensile strain along the *x* direction.

3.2 Effect of arsenic (As) substitution on Raman spectra

To verify the relations between the strong strain-dependent anisotropy and the quasi-1D P–P chains of SiP₂, we further investigated the Raman spectra by intentionally doping the arsenic atoms, as schematically shown in Fig. 3(a). We synthesized a series of doped SiP₂ with different stoichiometric arsenic concentrations of 0%, 10%, 20%, 30%, 40%, and 60%, as shown in Fig. S9 in the ESM.

Figure 3(b) shows the evolution of the Raman spectra of SiP₂-As10 (nominal As doping level of 10%) under strain applied from 0% to 2.6% along the *y* direction. Similar to pristine SiP₂, both B_{1g}³ and A_g⁶ modes shift toward lower wavenumbers. The evolution of the B_{1g}³ mode in our strained samples with different doping levels is shown in Fig. 3(c). Three important points should be addressed here. First, the B_{1g}³ mode at zero strain shows a blueshift with increased arsenic doping, showing a specific substitution of arsenic for P atoms in the SiP₂ crystal and remaining for further study. Second, when the strain gradually increases, the B_{1g}³ modes of all samples show redshifts. This implies a similar strain-dependent evolution along the *y* direction for all arsenic-doped SiP₂ flakes. Third, the average slope Δ for the B_{1g}³ mode significantly decreases with increasing arsenic doping level, as shown in Fig. 3(d). These results indicate that heavy arsenic atoms increase the bonding strength and further reduce the strain-dependent sensitivity and confirm that the quasi-1D P–P chains are directly related to the strong strain-dependent anisotropy of SiP₂.

3.3 PL spectra of strained SiP₂ with a wrinkled structure

To understand the evolution of the band gap associated with the P–P chains, which is the source of the conduction-band electron wave function, we performed PL measurements in strained SiP₂ flakes. The PET substrate generally shows a large PL background overlapping with the PL signals of SiP₂, which will cause technical difficulties for studying PL properties. Herein, we performed measurements for strain-engineered PL spectra by using an alternative method with a clean background (shown in Fig. S10 in the ESM), as described in the Experimental Section. As shown in Fig. 4(a), the local uniaxial strain is obtained by intentionally wrinkling a SiP₂ flake to form a bending structure on a pre-stretched flexible substrate, which has been widely used to produce strain with multiple wrinkles in layered materials [29]. The bottom panel of Fig. 4(a) shows the AFM image of an example of the wrinkle in a strained SiP₂ flake. The strain ε at the top of the wrinkle can be estimated as $\varepsilon \sim \pi^2 h \delta / (1 - \sigma^2) \lambda^2$, where σ is

Poisson's ratio of SiP₂, h is the thickness of the flake, and δ and λ are the height and width of the wrinkle, respectively [29]. These values can be obtained from the wrinkle geometry, as shown in the top panel of Fig. 4(b), and more details are shown in Fig. S11 in the ESM.

To understand the strain distribution around the wrinkle, we conducted a line scan for the PL measurements across the wrinkle, and the results are shown in Fig. 4(c). Note that the PL spectra show redshifts from the flat bottom to the top of the bent wrinkle. This indicates that strain reduces the band gap of SiP₂. The largest redshift of the PL spectra is observed on the top of the wrinkle, indicating that the maximum strain is achieved there, similar to a previous report on MoS₂ [29]. The evolution of the band gap energy with location is shown in the bottom panel of Fig. 4(b). The PL spectra obtained at the top of the wrinkle have a maximum redshift as high as 55 meV under a strain of 1.88% compared to that in the flat area, which indicates that the applied strain reduces the band gap. According to the above strain estimation, the maximum strains generated at the top of the three wrinkles in the same SiP₂ flake are 1.34%, 1.53%, and 1.88%, and the corresponding PL spectra are shown in Fig. 4(d). Figure 4(e) shows the evolution of the band gap with strain caused by wrinkles. With increased effective strain, the band gap energy decreases. The band gap of SiP₂ is modulated by strain with a modulation efficiency of 26 meV/% and displays a gradual redshift from the bottom to the top of the wrinkle at different angles from the P–P chain (shown in Fig. S12 in the ESM). Strain can only reduce the band gap energy of SiP₂ without causing symmetry breaking (shown in Fig. S13 in the ESM). These observations shed light on understanding the microscopic excitonic properties arising from the quasi-1D P–P chains in SiP₂.

4 Conclusions

In summary, we demonstrate strain engineering on anisotropic light–matter interactions in quasi-1D P–P chains of layered SiP₂. We find that the lattice structure and phonon vibration of SiP₂ can be manipulated with uniaxial strain, providing a unique means to design and control the light–matter interactions for atomically thin SiP₂-based devices. As the arsenic doping level increases, the absolute values of the slopes of the strain-dependent phonon energies decrease in the arsenic-doped SiP₂ samples. With PL measurements of the wrinkled SiP₂ samples, the PL peak shows a redshift, and the band gap energy decreases with increasing strain.

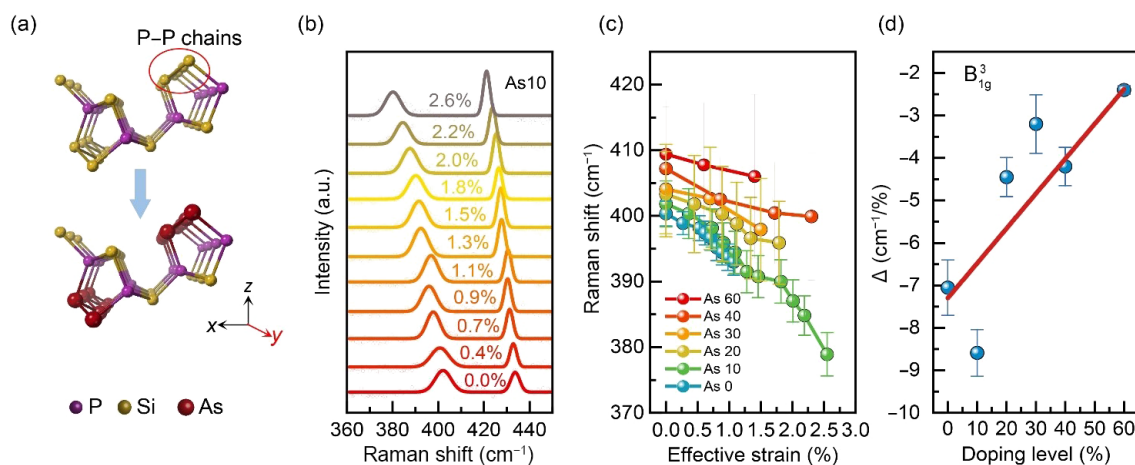


Figure 3 Raman spectra of As-doped SiP₂ under strain along the *y* direction. (a) Schematic depiction of substitution of the P atoms within the P–P chains by As atoms. (b) Evolution of Raman spectra of SiP₂-As10 (nominal As doping level of 10%) under tensile strain applied from 0% to 2.6% along the *y* direction. (c) Evolution of the strained B_{1g}³ Raman peak of doped SiP₂ with different As concentrations of 0%, 10%, 20%, 30%, 40%, and 60%. (d) The average slope Δ for the B_{1g}³ modes as a function of doping level.

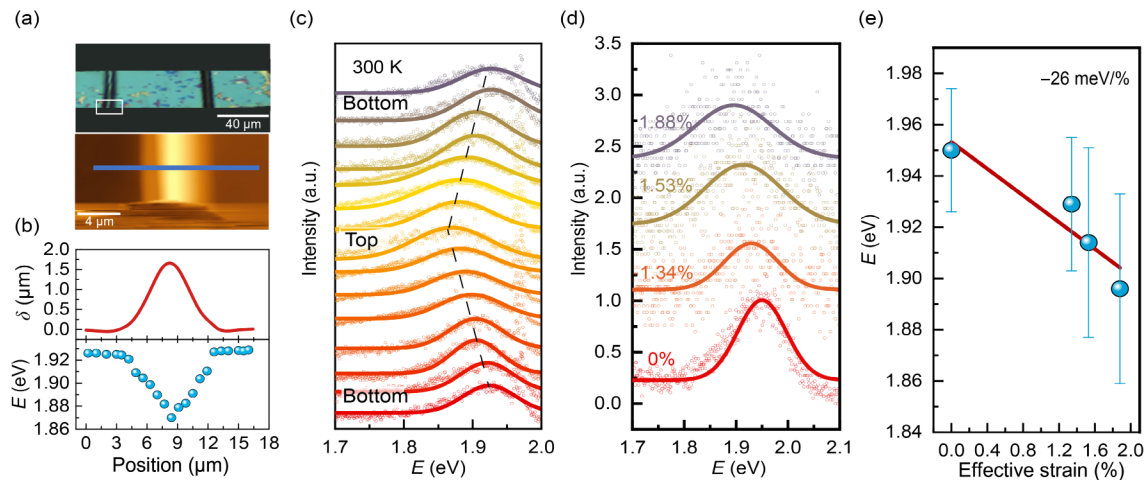


Figure 4 Photoluminescence of a strain-engineered wrinkled SiP₂ thin flake. (a) Optical image of a SiP₂ thin flake with a wrinkled structure (top panel) and AFM topography image of the area marked by a white rectangle (bottom panel). (b) Height profile (top panel) along the blue line crossing the wrinkle shown in the AFM image in (a). Based on the shape of the wrinkle, the induced tensile strain along the *y* direction on the top of the wrinkle can be estimated. The bottom panel shows the energy of the optical band gap at different positions along the blue line in (a). The energy of the optical band gap displays the largest redshift at the top of the wrinkle, where the largest tensile strain is induced. (c) The PL spectra measured along the blue line crossing the wrinkle. The hollow circles represent the original data, and the solid curves are obtained by Gaussian fitting. The black dashed line guides the evolution of the energy of the optical band gap, which displays a gradual redshift when the laser spot moves from the bottom to the top of the wrinkle. (d) PL spectra measured on the tops of three different wrinkles. The hollow circles represent the experimental data of the PL spectra, and the solid curves are obtained by Gaussian fitting. (e) Strain dependence of the energy of the optical band gap obtained from the Gaussian fittings in (d). A band gap modulation ΔE as large as ~ 55 meV is observed in a SiP₂ thin flake strained up to 1.88% along the *y* direction, with a modulation efficiency of 26 meV/%.

These observations suggest strain engineering as a powerful route to explore novel physics in anisotropic materials, opening additional opportunities for potential optics and optoelectronics applications.

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Electronic Supplementary Material: Supplementary Material ((1) measurement of sample length with applied strain in the *y* and *x* directions, (2) measurement method of sample length with applied strain, (3) details of the strain application procedure, (4) polarized Raman spectra of the B_{1g}³ mode under strain, (5) lattice vibrations with fourfold degeneracy of the B_{1g}³ mode, (6) peak intensity analysis of Raman spectra of SiP₂ under uniaxial tensile strain, (7) Measurement results of Poisson's ratio value, (8) Raman spectra of SiP_{2-x}As_x alloys under strain, (9) optical background of stretchable substrates, (10) strain analysis in the SiP₂ wrinkling structure, (11) PL spectra of the SiP₂ wrinkling structure along different crystal directions, and (12) polarized PL spectra under strain) is available in the online version of this article at <https://doi.org/10.1007/s12274-022-4315-5>.

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